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<u>L5</u>	trigger\$ near5 inoperat\$	585	<u>L5</u>
<u>L4</u>	trigger\$ near5 (inoperat\$ or run\$ or work\$ or stop\$)	15903	<u>L4</u>
<i>DB=PGPB; PLUR=YES; OP=ADJ</i>			
<u>L3</u>	L2 and inoperative	1	<u>L3</u>
<u>L2</u>	(object and trigger).ti.	1	<u>L2</u>
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WEST[Generate Collection](#)[Print](#)**Search Results - Record(s) 1 through 3 of 3 returned.**☐ 1. Document ID: US 6286102 B1

L15: Entry 1 of 3

File: USPT

Sep 4, 2001

US-PAT-NO: 6286102

DOCUMENT-IDENTIFIER: US 6286102 B1

TITLE: Selective wireless disablement for computers passing through a security checkpoint

DATE-ISSUED: September 4, 2001

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Cromer; Daryl	Cary	NC		
Dayan; Richard	Wake Forest	NC		
Locker; Howard	Cary	NC		
Steinmetz; Mike	Cary	NC		
Ward; Jim	Raleigh	NC		

US-CL-CURRENT: 713/200

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWC	Draw Desc	Image
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☐ 2. Document ID: US 5970227 A

L15: Entry 2 of 3

File: USPT

Oct 19, 1999

US-PAT-NO: 5970227

DOCUMENT-IDENTIFIER: US 5970227 A

TITLE: Wireless proximity detector security feature

DATE-ISSUED: October 19, 1999

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Dayan; Richard A.	Wake Forest	NC		
McGovern; Joseph P.	Apex	NC		
Newman; Palmer E.	Apex	NC		

US-CL-CURRENT: 713/200; 340/5.3, 340/5.61, 713/183

Full

Title

Citation

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KWIC

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☐ 3. Document ID: US 5496992 A

L15: Entry 3 of 3

File: USPT

Mar 5, 1996

US-PAT-NO: 5496992
DOCUMENT-IDENTIFIER: US 5496992 A

TITLE: Dual trigger multiplexed data entry terminal

DATE-ISSUED: March 5, 1996

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Madan; Esteban C.	Duluth	GA		
Beebe; Randolph R.	Duluth	GA		
Stanfield; Teresa H.	Lawrenceville	GA		

US-CL-CURRENT: 235/472.02; 235/462.48, 341/23, 708/144

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Abugov, R.;
Semiconductor Manufacturing Science Symposium, 1992. ISMSS 1992.,
IEEE/SEMI International , 15-16 June 1992
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